DS05-11143-1E

# **MEMORY Un-buffered** $4 \text{ M} \times 72 \text{ BIT}$ SYNCHRONOUS DYNAMIC RAM DIMM

## MB8504S072CA-102/-103/-102L/-103L

168-pin, 4 Clock, 1-bank, based on 4 M × 16 Bit SDRAMs with SPD

#### ■ DESCRIPTION

The Fujitsu MB8504S072CA is a fully decoded, CMOS Synchronous Dynamic Random Access Memory (SDRAM) Module consisting of five MB81F641642C devices which organized as four banks of 4 M × 16 bits and a 2K-bit serial EEPROM on a 168-pin glass-epoxy substrate.

The MB8504S072CA features a fully synchronous operation referenced to a positive edge clock whereby all operations are synchronized at a clock input which enables high performance and simple user interface coexistence.

The MB8504S072CA is optimized for those applications requiring high speed, high performance and large memory storage, and high density memory organizations.

This module is ideally suited for workstations, PCs, laser printers, and other applications where a simple interface is needed.

#### **■ PRODUCT LINE & FEATURES**

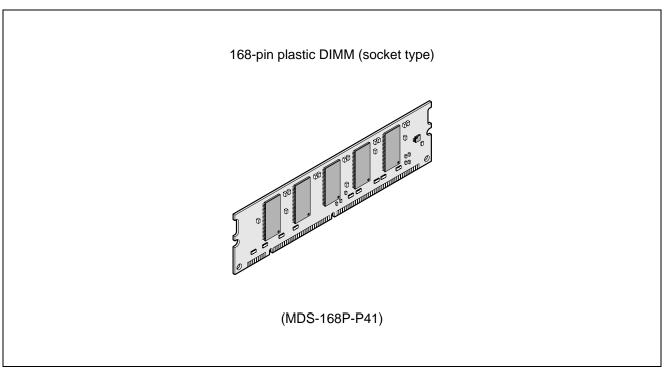
Para	meter	MB8504S072CA-102/-102L	MB8504S072CA-103/-103L
CL-trcd-trp		2-2-2 clk min.	3-2-2 clk min.
Clock Frequency		100 MHz max.	100 MHz max.
Burst Mode Cycle Time		10 ns min.	10 ns min.
Output Valid from Clo	ck	6 ns max. (CL = 2)	6 ns max. (CL = 3)
	Two Banks Active	3424 mW max.	3424 mW max.
Power Dissipation	Self Refresh Mode	18.0 mW max. (std. power) 9.0 mW max. (low power)	18.0 mW max. (std. power) 9.0 mW max. (low power)

- Un-buffered 168-pin DIMM Socket Type (Lead pitch: 1.27 mm)
- Conformed to JEDEC Standard (4 CLK)
- Organization: 4,194,304 words × 72 bits
- 3.3 V ±0.3 V Supply Voltage
- All input/output LVTTL compatible
- Conformed to Intel PC/100 spec

- 4096 Refresh Cycle every 65.6 ms
- · Auto and Self Refresh
- CKE Power Down Mode
- DQM Byte Masking (Read/Write)
- Memory: MB81F641642C (4 M × 16, 4-bank) × 5 pcs Serial Presence Detect (SPD) with Serial EEPROM: Intel SPD spec Rev 1.2A Format

1.375" (height)  $\times$  5.25" (length)  $\times$  0.157" (thickness)

### **■ PACKAGE**

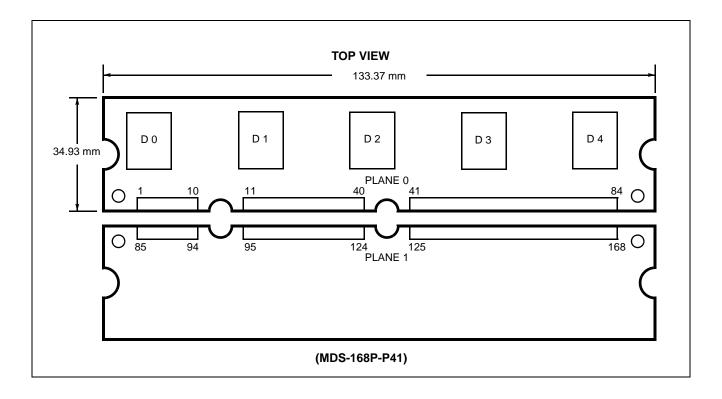


### **Package and Ordering Information**

- 168-pin DIMM, order as MB8504S072CA-xxxDG (DG = std. power ver., Gold Pad) MB8504S072CA-xxxLDG(LDG = low power ver., Gold Pad)

### **■ PIN ASSIGNMENTS**

Pin No.	Signal Name	Pin No.	Signal Name	Pin No.	Signal Name	Pin No.	Signal Name	Pin No.	Signal Name	Pin No.	Signal Name
1	Vss	29	DQMB <sub>1</sub>	57	DQ <sub>18</sub>	85	Vss	113	DQMB₅	141	DQ <sub>50</sub>
2	DQ₀	30	<del>CS</del> ₀	58	DQ <sub>19</sub>	86	DQ <sub>32</sub>	114	N.C.	142	DQ <sub>51</sub>
3	DQ <sub>1</sub>	31	N.C.	59	Vcc	87	DQ <sub>33</sub>	115	RAS	143	Vcc
4	DQ <sub>2</sub>	32	Vss	60	DQ <sub>20</sub>	88	DQ <sub>34</sub>	116	Vss	144	DQ <sub>52</sub>
5	DQ₃	33	A <sub>0</sub>	61	N.C.	89	DQ <sub>35</sub>	117	A <sub>1</sub>	145	N.C.
6	Vcc	34	A <sub>2</sub>	62	N.C.	90	Vcc	118	<b>A</b> 3	146	N.C.
7	DQ <sub>4</sub>	35	A <sub>4</sub>	63	N.C.	91	DQ <sub>36</sub>	119	<b>A</b> 5	147	N.C.
8	DQ <sub>5</sub>	36	<b>A</b> 6	64	Vss	92	DQ <sub>37</sub>	120	A <sub>7</sub>	148	Vss
9	DQ <sub>6</sub>	37	A8	65	DQ <sub>21</sub>	93	DQ <sub>38</sub>	121	<b>A</b> 9	149	DQ <sub>53</sub>
10	DQ <sub>7</sub>	38	A <sub>10</sub>	66	DQ <sub>22</sub>	94	DQ <sub>39</sub>	122	BA <sub>0</sub>	150	DQ <sub>54</sub>
11	DQ <sub>8</sub>	39	BA <sub>1</sub>	67	DQ <sub>23</sub>	95	DQ <sub>40</sub>	123	A <sub>11</sub>	151	DQ <sub>55</sub>
12	Vss	40	Vcc	68	Vss	96	Vss	124	Vcc	152	Vss
13	DQ <sub>9</sub>	41	Vcc	69	DQ <sub>24</sub>	97	DQ <sub>41</sub>	125	CLK <sub>1</sub>	153	DQ <sub>56</sub>
14	DQ <sub>10</sub>	42	CLK <sub>0</sub>	70	DQ <sub>25</sub>	98	DQ <sub>42</sub>	126	N.C.	154	DQ <sub>57</sub>
15	DQ <sub>11</sub>	43	Vss	71	DQ <sub>26</sub>	99	DQ <sub>43</sub>	127	Vss	155	DQ <sub>58</sub>
16	DQ <sub>12</sub>	44	N.C.	72	DQ <sub>27</sub>	100	DQ <sub>44</sub>	128	CKE <sub>0</sub>	156	DQ <sub>59</sub>
17	DQ <sub>13</sub>	45	$\overline{\text{CS}}_2$	73	Vcc	101	DQ <sub>45</sub>	129	N.C.	157	Vcc
18	Vcc	46	DQMB <sub>2</sub>	74	DQ <sub>28</sub>	102	Vcc	130	DQMB <sub>6</sub>	158	DQ <sub>60</sub>
19	DQ <sub>14</sub>	47	DQMB <sub>3</sub>	75	DQ <sub>29</sub>	103	DQ <sub>46</sub>	131	DQMB <sub>7</sub>	159	DQ <sub>61</sub>
20	DQ <sub>15</sub>	48	N.C.	76	DQ <sub>30</sub>	104	DQ <sub>47</sub>	132	N.C.	160	DQ <sub>62</sub>
21	CB <sub>0</sub>	49	Vcc	77	DQ <sub>31</sub>	105	CB <sub>4</sub>	133	Vcc	161	DQ <sub>63</sub>
22	CB <sub>1</sub>	50	N.C.	78	Vss	106	CB <sub>5</sub>	134	N.C.	162	Vss
23	Vss	51	N.C.	79	CLK <sub>2</sub>	107	Vss	135	N.C.	163	CLK <sub>3</sub>
24	N.C.	52	CB <sub>2</sub>	80	N.C.	108	N.C.	136	CB <sub>6</sub>	164	N.C.
25	N.C.	53	СВз	81	N.C. (WP)	109	N.C.	137	CB <sub>7</sub>	165	SA <sub>0</sub>
26	Vcc	54	Vss	82	SDA	110	Vcc	138	Vss	166	SA <sub>1</sub>
27	WE	55	DQ <sub>16</sub>	83	SCL	111	CAS	139	DQ <sub>48</sub>	167	SA <sub>2</sub>
28	DQMB <sub>0</sub>	56	DQ <sub>17</sub>	84	Vcc	112	DQMB <sub>4</sub>	140	DQ <sub>49</sub>	168	Vcc



#### **■ PIN DESCRIPTIONS**

Symbol	I/O	Function	Symbol	I/O	Function
A <sub>0</sub> to A <sub>11</sub>	I	Address Input	DQ <sub>0</sub> to DQ <sub>63</sub>	I/O	Data Input/Data Output
BA <sub>0</sub> , BA <sub>1</sub>	I	Bank Select (Bank Address)	CB <sub>0</sub> to CB <sub>7</sub>	I/O	Data I/O for ECC
RAS	I	Row Address Strobe	Vcc	_	Power Supply (+3.3 V)
CAS	I	Column Address Strobe	Vss	_	Ground (0 V)
WE	I	Write Enable	N.C.	_	No Connection
DQMB <sub>0</sub> to DQMB <sub>7</sub>	I	Data (DQ) Mask	SA <sub>0</sub> to SA <sub>2</sub>	I	Serial PD Address Input
CLK₀ to CLK₃	I	Clock Input	SCL	I	Serial PD Clock
CKE₀	I	Clock Enable	SDA	I/O	Serial PD Address/Data Input/Output
$\overline{\text{CS}}_0, \overline{\text{CS}}_2$	I	Chip Select	WP	_	Serial PD Write Protect

#### **■ SERIAL-PD INFORMATION**

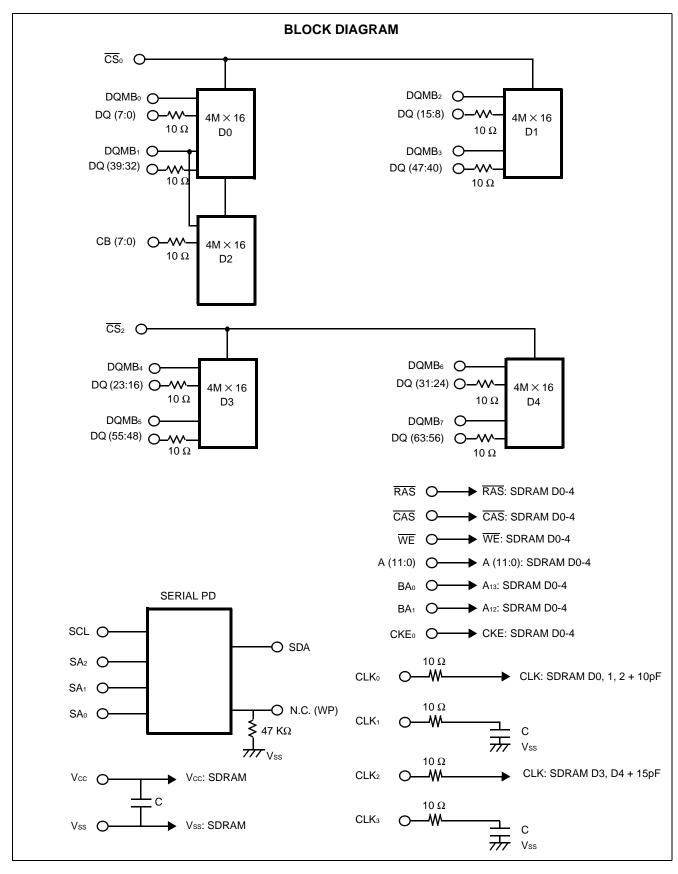
_			Hex \	/alue
Byte	Function Described		-102/ 102L	-103/ 103L
0	Defines Number of Bytes Written into Serial Memory at Module Manufacture	128 Byte	80h	80h
1	Total Number of Bytes of SPD Memory Device	256 Byte	08h	08h
2	Fundamental Memory Type	SDRAM	04h	04h
2	Number of Row Addresses	12	0Ch	0411 0Ch
] ]	Number of Column Addresses	8	08h	08h
1 5	Number of Module Banks	1 bank	01h	01h
6	Data Width	72 bit	48h	48h
2 3 4 5 6 7	Data Width (Continuation)	+0	00h	00h
8	Interface Type	LVŤTL	01h	01h
9	SDRAM Cycle Time (Highest CAS Latency)	10/10 ns	Ã0h	Ă0h
10	SDRAM Access from Clock (Highest CAS Latency)	6/6 ns	60h	60h
11	DIMM Configuration Type	ECC	02h	02h
12	Refresh Rate/Type	Self, Normal	80h	80h
13	Primary SDRAM Width	×16	10h	10h
14	Error Checking SDRAM Width	×16	10h	10h
15	Minimum Clock Delay for Back to Back Random Column Addresses	1 Cycle	01h	01h
16	Burst Lengths Supported	1, 2, 4, 8, Page	8Fh	8Fh
17	Number of Banks on Each SDRAM Device	4 bank	04h	04h
18	CAS Latency Supported	2, 3	06h	06h
19	CS Latency Control Con	0	01h	01h
20	Write Latency	0	01h	01h
21	SDRAM Module Attributes	UN-buffer	00h	00h
22	SDRAM Device Attributes : General	*1	0Eh	0Eh
23	SDRAM Cycle Time (2nd. Highest CAS Latency)	10/15 ns	A0h	F0h
24	SDRAM Access from Clock (2nd. Highest CAS Latency)	6/8 ns	60h	80h
25	SDRAM Cycle Time (3rd. Highest CAS Latency)	No Support	00h	00h
26	SDRAM Access from Clock (3rd. Highest CAS Latency)	No Support	00h	00h
27	Minimum Row Precharge Time (trp)	20/20 ns	14h	14h
28	Row Activate to Row Activate Minimum (trrd)	20/20 ns	14h	14h
29	RAS to CAS Delay Min. (trcd)	20/20 ns	14h	14h
30 31	Minimum RAS Pulse Width Module Bank Density	50/50 ns 32 MByte	32h	32h 08h
32	Command and Address Signal Input Setup Time	2 ns	08h 20h	20h
33	Command and Address Signal Input Hold Time	1 ns	10h	10h
34	Data Signal Input Setup Time	2 ns	20h	20h
35	Data Signal Input Hold Time	1 ns	10h	10h
36 to 61	Unused Storage Locations	_	00h	00h
62	SPD Data Revision Code	1.2	12h	12h
63	Checksum for Byte 0 to 62	*2	1Eh	8Eh
64 to 71	Manufacturer's JEDEC ID Code Per JEP-108E	Optional	00h	00h
72	Manufacturing Location	Optional	00h	00h
73 to 90	Manufacturer's Part Number	Optional	00h	00h
91 to 92	Revision Code	Optional	00h	00h
93 to 94	Manufacturing Data	Optional	00h	00h
95 to 98	Assembly Serial Number	Optional	00h	00h
99 to 125	Manufacturer Specific Data	Optional	00h	00h
126	Intel Specification Frequency	100 MHz	64h	64h
127	Intel Specification Details for 100 MHz Support	CL = 2, 3/3	AFh	ADh
128+	Unused Storage Locations	_		

**Note:** Any write operation must NOT be executed into the addresses of Byte 0 to Byte 127. Some or all data stored into Byte 0 to Byte 127 may be broken.

#### \*1. Byte 22: SDRAM Device Attributes

Bit7	Bit6	Bit5	Bit4	Bit3	Bit2	Bit1	Bit0
TBD	TBD	Upper Vcc tolerance	Lower Vcc tolerance	Supports Write 1 /Read Burst	Supports Precharge All	Supports Auto- Precharge	Suppo <u>rts</u> Early RAS Precharge
0	0	0	0	1	1	1	0

\*2. Byte 63: Checksum for Byte 0 to 62
This byte is the checksum for Byte 0 through 62. This byte contains the value of the low 8-bits of the arithmetic sum of Byte 0 through 62.



### ■ ABSOLUTE MAXIMUM RATINGS (See WARNING)

Parameter	Symbol	Va	lue	Unit
Farameter	Symbol	Min.	Max.	Onit
Supply Voltage*	Vcc	-0.5	+4.6	V
Input Voltage*	Vin	-0.5	+4.6	V
Output Voltage*	Vоит	-0.5	+4.6	V
Storage Temperature	Тѕтс	<b>–</b> 55	+125	°C
Power Dissipation	PD	_	5.0	W
Output Current (D.C.)	Іоит	-50	+50	mA

<sup>\*:</sup> Voltages referenced to Vss (= 0 V)

WARNING: Semiconductor devices can be permanently damaged by application of stress (voltage, current, temperature, etc.) in excess of absolute maximum ratings. Do not exceed these ratings.

#### ■ RECOMMENDED OPERATING CONDITIONS

Parameter	Notes	Symbol		Value		Unit
Farameter	Notes	Зупівої	Min.	Тур.	Max.	Unit
Supply Voltage	*1	Vcc	3.0	3.3	3.6	V
Supply Voltage	I	Vss	0	0	0	V
Input High Voltage, All Inputs	*1, 2	ViH	2.0	_	Vcc +0.5	V
Input Low Voltage, All Inputs	*1, 3	VIL	-0.5	_	0.8	V
Ambient Temperature		TA	0	_	+70	°C

<sup>\*1.</sup> Voltages referenced to Vss (=0V)

WARNING: The recommended operating conditions are required in order to ensure the normal operation of the semiconductor device. All of the device's electrical characteristics are warranted when the device is operated within these ranges.

> Always use semiconductor devices within their recommended operating conditionranges. Operation outside these ranges may adversely affect reliability and could result in device failure.

> No warranty is made with respect to uses, operating conditions, or combinations not represented on the data sheet. Users considering application outside the listed conditions are advised to contact their FUJITSU representatives beforehand.

<sup>\*2.</sup> Overshoot limit:  $V_{H}$  (max.) =  $V_{CC}$  +1.5 V with a pulse-width  $\leq 5$  ns.

<sup>\*3.</sup> Undershoot limit:  $V_{\perp}$  (min.) = -1.5 V with a pulse-width  $\leq 5$  ns.

### **■ CAPACITANCE**

 $(Vcc = +3.3 \text{ V}, f = 1 \text{ MHz}, T_A = +25^{\circ}\text{C})$ 

Parame	hor	Symbol	Va	lue	Unit
Parame	lei	Symbol	Min.	Max.	Unit
	A <sub>0</sub> to A <sub>11</sub> , BA <sub>0</sub> , BA <sub>1</sub>	C <sub>IN1</sub>	_	T.B.D.	pF
	RAS, CAS, WE	C <sub>IN2</sub>	_	T.B.D.	pF
	$\overline{\text{CS}}_{0}, \overline{\text{CS}}_{2}$	Сімз	_	T.B.D.	pF
Innut Canacitanas	CKE <sub>0</sub>	C <sub>IN4</sub>	_	T.B.D.	pF
Input Capacitance	CLK <sub>0</sub> to CLK <sub>3</sub>	C <sub>IN5</sub>	_	T.B.D.	pF
	DQMB <sub>0</sub> to DQMB <sub>7</sub>	CIN6	_	T.B.D.	pF
	SCL	Cscl	_	T.B.D.	pF
	SA <sub>0</sub> , SA <sub>1</sub> , SA <sub>2</sub>	Csa	_	T.B.D.	pF
	SDA	Csda	_	T.B.D.	pF
Input/Output Capacitance	DQ <sub>0</sub> to DQ <sub>63</sub>	CDQ	_	T.B.D.	pF
	CB <sub>0</sub> to CB <sub>7</sub>	Ссв	_	T.B.D.	pF

### **■ DC CHARACTERISTICS**

(At recommended operating conditions unless otherwise noted.) Notes 1, 2

					Value		
Parameter	Notes	Symbol	Condition		Ma	ax.	Unit
		,		Min.	std. ver.	low ver.	
Operating Current (Average Power Supply Current)	*3	Icc1s	Burst Length = 4, tRC = min  for BL = 4, tCK = min, One Bank Active, Outputs Open, Address changed up to 3 times during $tRC(min.)$ , $0 \text{ V} \leq VIN \leq VCC$	_	525		mA
	Icc1D		Burst Length = 4 (each Bank), tree = min for BL = 4 (each Bank), tex = min, Two Banks Active, Outputs Open, Address changed up to 3 times during tree(min.), $0 \text{ V} \leq \text{V}_{\text{IN}} \leq \text{V}_{\text{CC}}$	_	— 950		mA
		ICC2P	$CKE = V_{IL}, t_{CK} = min,$ All Banks Idle, Power Down Mode, $0 \ V \le V_{IN} \le V_{CC}$	_	10	5	mA
		Icc2PS	$\label{eq:ck} \begin{split} & CKE = V_{IL}, \\ & CLK = V_{IH} \text{ or } V_{IL}, \\ & All \text{ Banks Idle,} \\ & Power \text{ Down Mode,} \\ & 0  V \leq V_{IN} \leq V_{CC} \end{split}$	_	5	2.5	mA
Precharge Standby Current (Power Supply Current)	*3	Ісс2N	CKE = VIH, tck = min, All Banks Idle, NOP commands only, Input signals (except to CMD) are changed one time during 3 clock cycles, 0 V ≤ VIN ≤ VCC	_	75		mA
		Icc2NS	CKE = V <sub>IH</sub> , CLK = V <sub>IH</sub> or V <sub>IL</sub> , All Banks Idle, Input Signals are Stable, 0 V ≤ V <sub>IN</sub> ≤ V <sub>CC</sub>		10		mA

(Continued)

#### (Continued)

				Value		
Parameter Notes	Symbol	Condition		Ma	ax.	Unit
			Min.	std. ver.	low ver.	
	Іссзр	CKE = V <sub>IL</sub> , tc <sub>K</sub> = min, Any Bank Active, 0 V ≤ V <sub>IN</sub> ≤ V <sub>CC</sub>	_	10	5	mA
	Іссзрѕ	$ \begin{array}{l} CKE = V_{IL}, \\ CLK = V_{IH} \ or \ V_{IL}, \\ Any \ Bank \ Active, \\ 0 \ V \leq V_{IN} \leq V_{CC} \\ \end{array} $	_	5	2.5	mA
Active Standby Current (Power Supply Current)	Іссзи	CKE = V <sub>IH</sub> , t <sub>CK</sub> = min, Any Bank Active, NOP commands only, Input signals (except to CMD) are changed one time during 3 clock cycles, 0 V ≤ V <sub>IN</sub> ≤ V <sub>CC</sub>	_	12	25	mA
	Іссзиѕ	CKE = VIH, CLK = VIH or VIL, Any Bank Active, $0 \text{ V} \leq \text{V}_{\text{IN}} \leq \text{V}_{\text{CC}}$	_	1	mA	
Burst Mode Current (Average Power Supply Current)	lcc4	tck = min, Gapless data, Burst Length = 4, Outputs open, Multiple-banks Active, 0 V ≤ V <sub>IN</sub> ≤ V <sub>CC</sub>	_	425		mA
Auto-refresh Current (Average Power Supply Current)	lccs	Auto Refresh, $t_{CK} = min$ , $t_{RC} = min$ , $0 \text{ V} \leq V_{IN} \leq V_{CC}$	_	12	00	mA
Self-refresh Current (Average Power Supply Current)	lcc <sub>6</sub>	Self-refresh, tc $\kappa$ = min, CKE $\leq$ 0.2 V, 0 V $\leq$ VIN $\leq$ Vcc	_	5	2.5	mA
Input Leakage Current (All Inputs)	lu	$0 \text{ V} \le V_{IN} \le V_{CC}$ All other pins not under test = $0 \text{ V}$	-40	40		μΑ
Output Leakage Current	ILO	Output is disabled (Hi-Z) 0 V ≤ V <sub>IN</sub> ≤ V <sub>CC</sub>	-10	10		μΑ
LVTTL Output High Voltage *4	Voн	Iон = −2.0 mA	2.4	_	_	V
LVTTL Output Low Voltage *2	Vol	IoL = +2.0 mA	_	0	.4	V

- Notes: \*1. An initial pause (DESL on NOP) of 200 µs is required after power-on followed by a minimum of eight Auto-refresh cycles.
  - \*2. DC characteristics is the Serial PD standby state (V<sub>IN</sub> = GND or V<sub>CC</sub>).
  - \*3. Icc depends on the output termination, load conditions, clock cycle rate and signal clock rate. The specified values are obtained with the output open and no termination resistors.
  - \*4. Voltages referenced to Vss (= 0 V)

## ■ AC CHARACTERISTICS

(SDRAM Component Specifications) Notes 1, 2, 3

### (1) BASE CHARACTERISTICS

(At recommended operating conditions unless otherwise noted.)

No.	Parameter No	otes	Symbol	MB8504 -102/	S072CA -102L	MB8504 -103/-	S072CA -103L	Unit
				Min.	Max.	Min.	Max.	
1	Clock Period	CL = 2	<b>t</b> ск2	10	_	15	_	ns
'	Clock Fellod	CL = 3	<b>t</b> скз	10	_	10	_	115
2	Clock High Time		tсн	3	_	3	_	ns
3	Clock Low Time		<b>t</b> cL	3	_	3	_	ns
4	Input Setup Time		<b>t</b> sı	2	_	2	_	ns
5	Input Hold Time		tнı	1	_	1	_	ns
6	Output Valid from Clock *4, *5	CL = 2	t <sub>AC2</sub>	_	6	_	8	ns
0	(tclk = min) 4, 5	CL = 3	t <sub>AC3</sub>	_	6	_	6	115
7	Output in Low-Z		<b>t</b> LZ	0	_	0	_	ns
8	Output in High-Z *6	CL = 2	<b>t</b> HZ2	3	6	3	8	nc
0	Output III r light-2	CL = 3	<b>t</b> HZ3	3	6	3	6	ns
9	Output Hold Time		tон	3	_	3	_	ns
10	Time between Refresh		<b>t</b> REF	_	65.6	_	65.6	ms
11	Transition Time		t⊤	0.5	2	0.5	2	ns
12	CKE Setup Time for Power Down E	xit Time	<b>t</b> cksp	3	_	3	_	ns

### (2) BASE VALUES FOR CLOCK COUNT/LATENCY

No.	Parameter		Symbol	MB8504 -102/-	S072CA -102L	MB8504 -103/-	Unit	
				Min.	Max.	Min.	Max.	
1	RAS Cycle Time	*7	<b>t</b> RC	70	_	70	_	ns
2	RAS Precharge Time		<b>t</b> RP	20	_	20	_	ns
3	RAS Active Time		tras	50	110000	50	110000	ns
4	RAS to CAS Delay Time	*8	<b>t</b> RCD	20	_	20	_	ns
5	Write Recovery Time		twr	10	_	10	_	ns
6	Data-in to Precharge Lead Time		<b>t</b> DPL	10	_	10	_	ns
7	Data-in to Active/Refresh Command Period	CL = 2	tDAL2	1 cyc + trp	_	1 cyc + trp	_	ns
'	Data-III to Active/Reflesh Confinant Feriod	CL = 3	t <sub>DAL3</sub>	2 cyc + trp	_	2 cyc + trp	_	115
8	Mode Register Set Cycle Time		trsc	20	_	20	_	ns
9	RAS to RAS Bank Active Delay Time		<b>t</b> rrd	20	_	20	_	ns

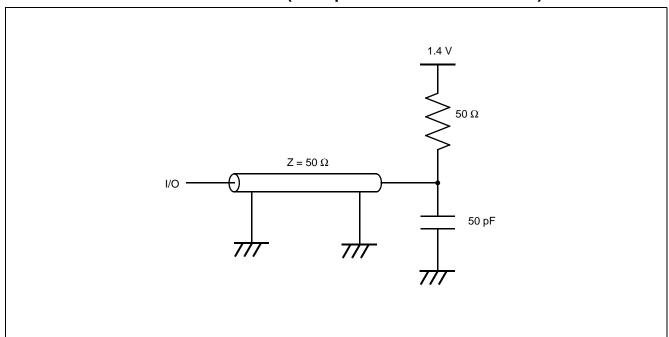
### (3) CLOCK COUNT FORMULA (\*9)

### (4) LATENCY (The latency values on these parameters are fixed regardless of clock period.)

No.	Parameter		Symbol	MB8504S072CA -102/-102L	MB8504S072CA -103/-103L	Unit
1	CKE to Clock Disable		Іске	1	1	Cycle
2	DQM to Output in High-Z		IDQZ	2	2	Cycle
3	DQM to Input Data Delay		IDQD	0	0	Cycle
4	Last Output to Write Command Delay		lowd	2	2	Cycle
5	Write Command to Input Data Delay		I <sub>DWD</sub>	0	0	Cycle
6	Precharge to Output in High-Z Delay  CL =  CL =		IROH2	2	2	Cycle
0			Ігонз	3	3	
7	Burst Stop Command to Output in High-Z Delay CL = CL =		I <sub>BSH2</sub>	2	2	Cyrolo
7			Івѕнз	3	3	Cycle
8	CAS to CAS Delay (min)		Iccd	1	1	Cycle
9	CAS Bank Delay (min)		Ісво	1	1	Cycle

- **Notes:** \*1. An initial pause (DESL on NOP) of 200 μs is required after power-up followed by a minimum of eight Auto-refresh cycles.
  - \*2. 1.4 V or V<sub>REF</sub> is the reference level for measuring timing of signals. Transition times are measured between V<sub>IH</sub> (min) and V<sub>IL</sub> (max).
  - \*3. AC characteristics assume  $t_T$  = 1 ns and 50 pF of capacitance load.
  - \*4. Assumes tRCD is satisfied.
  - \*5. tac also specifies the access time at burst mode except for first access.
  - \*6. Specified where output buffer is no longer driven.
  - \*7. Actual clock count of trc (Irc) will be sum of clock count of tras (Iras) and trp (Irp).
  - \*8. Operation within the trcd (min) ensures that access time is determined by trcd (min) +tac (max); if trcd is greater than the specified trcd (min), access time is determined by trac.
  - \*9. All base values are measured from the clock edge at the command input to the clock edge for the next command input.
    - All clock counts are calculated by a simple formula:
    - clock count equals base value divided by clock period (round off to a whole number).

### ■ AC OPERATING TEST CONDITION (Example of AC Test Load Circuit)



<sup>\*</sup>Source: See MB81F641642C Data Sheet for details on the electrical.

### ■ SERIAL PRESENCE DETECT(SPD) FUNCTION

#### 1. PIN DESCRIPTIONS

#### **SCL (Serial Clock)**

SCL input is used to clock all data input/output of SPD.

#### SDA (Serial Data)

SDA is a common pin used for all data input/output of SPD. The SDA pull-up resistor is required due to the open-drain output.

#### SA<sub>0</sub>, SA<sub>1</sub>, SA<sub>2</sub> (Address)

Address inputs are used to set the least significant three bits of the eight bits slave address. The address inputs must be fixed to select a particular module and the fixed address of each module must be different each other.

#### 2. SPD OPERATIONS

#### **CLOCK and DATA CONVENTION**

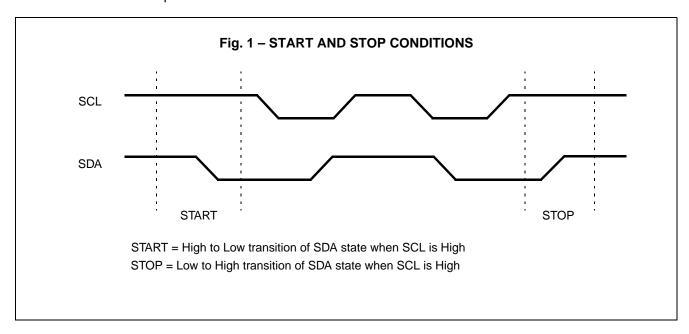
Data states on the SDA can change only during SC L= Low. SDA state changes during SCL = High are indicated start and stop conditions. Refer to Fig. 1 below.

#### START CONDITION

All commands are preceded by a start condition, which is a transition of SDA state from High to Low when SCL = High. SPD will not respond to any command until this condition has been met.

#### STOP CONDITION

All read or write operation must be terminated by a stop condition, which is a transition of SDA state from Low to High when SCL = High. The stop condition is also used to make the SPD into the state of standby power mode after a read sequence.



#### **ACKNOWLEDGE**

Acknowledge is a software convention used to indicate successful data transfer. The transmitting device, either master or slave, will release the bus after transmitting eight bits. During the ninth clock cycle the receiver will put the SDA line to Low in order to acknowledge that it received the eight bits of data.

The SPD will respond with an acknowledge when it received the start condition followed by slave address issued by master.

In the read operation, the SPD will transmit eight bits of data, release the SDA line and monitor the line for an acknowledge. If an acknowledge is detected and no stop condition is issued by master, the SPD will continue to transmit data. If an acknowledge is not detected, the SPD will terminated further data transmissions. The master must then issue a stop condition to return the SPD to the standby power mode.

In the write operation, upon receipt of eight bits of data the SPD will respond with an acknowledge, and await the next eight bits of data, again responding with an acknowledge until the stop condition is issued by master.

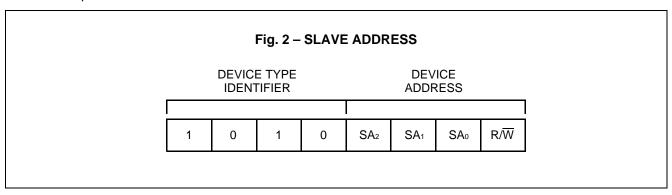
#### SLAVE ADDRESS ADDRESSING

Following a start condition, the master must output the eight bits slave address. The most significant four bits of the slave address are device type identifier. For the SPD this is fixed as 1010[B]. Refer to the Fig. 2 below.

The next three significant bits are used to select a particular device. A system could have up to eight SPD devices —namely up to eight modules— on the bus. The eight addresses for eight SPD devices are defined by the state of the SA<sub>0</sub>, SA<sub>1</sub> and SA<sub>2</sub> inputs.

The last bit of the slave address defines the operation to be performed. When  $R/\overline{W}$  bit is "1", a read operation is selected, when  $R/\overline{W}$  bit is "0", a write operation is selected.

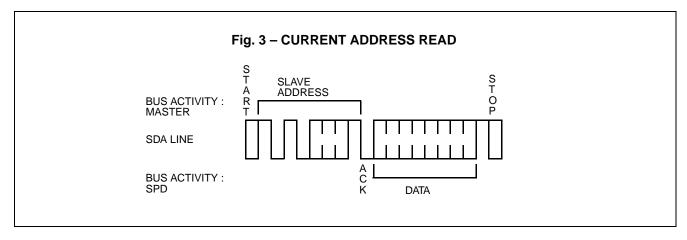
Following the start condition, the SPD monitors the SDA line comparing the slave address being transmitted with its slave address (device type and state of  $SA_0$ ,  $SA_1$ , and  $SA_2$  inputs). Upon a correct compare the SPD outputs an acknowledge on the SDA line. Depending on the state of the  $R/\overline{W}$  bit, the SPD will execute a read or write operation.



#### 3. READ OPERATIONS

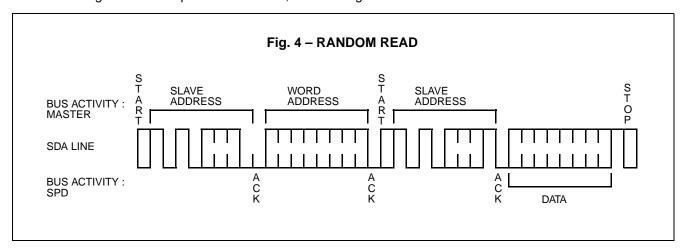
#### **CURRENT ADDRESS READ**

Internally the SPD contains an address counter that maintains the address of the last data accessed, incremented by one. Therefore, if the last access (either a read or write operation) was to address(n), the next read operation would access data from address(n+1). Upon receipt of the slave address with the  $R/\overline{W}$  bit = "1", the SPD issues an acknowledge and transmits the eight bits of data during the next eight clock cycles. The master terminates this transmission by issuing a stop condition, omitting the ninth clock cycle acknowledge. Refer to Fig. 3 for the sequence of address, acknowledge and data transfer.



#### **RANDOM READ**

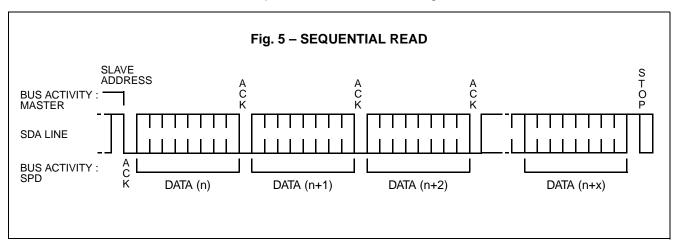
Random Read operations allow the master to access any memory location in a random manner. Prior to issuing the slave address with the  $R/\overline{W}$  bit = "1", the master must first perform a "dummy" write operation on the SPD. The master issues the start condition, and the slave address followed by the word address. After the word address acknowledge, the master immediately reissues the start condition and the slave address with the  $R/\overline{W}$  bit = "1". This will be followed by an acknowledge from the SPD and then by the eight bits of data. The master terminates this transmission by issuing a stop condition, omitting the ninth clock cycle acknowledge. Refer to Fig. 4 for the sequence of address, acknowledge and data transfer.



#### **SEQUENTIAL READ**

Sequential Read can be initiated as either a current address read or random read. The first data are transmitted as with the other read mode, however, the master now responds with an acknowledge, indicating it requires additional data. The SPD continues to output data for each acknowledge received. The master terminates this transmission by issuing a stop condition, omitting the ninth clock cycle acknowledge. Refer to Fig. 5 for the sequence of address, acknowledge and data transfer.

The data output is sequential, with the data from address(n) followed by the data from address(n+1). The address counter for read operations increments all address bits, allowing the entire memory contents to be serially read during one operation. At the end of the address space (address 255), the counter "rolls over" to address 0 and the SPD continues to output data for each acknowledge received.



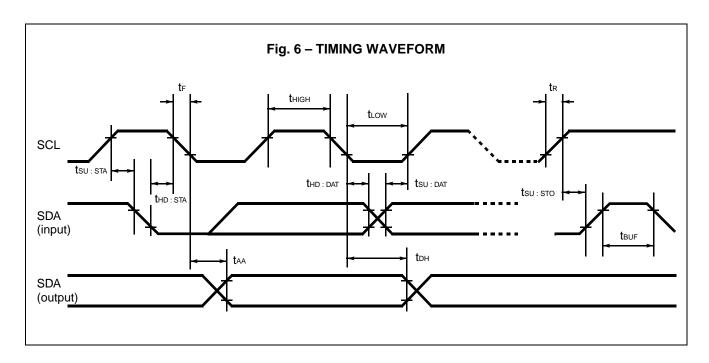
#### 4. DC CHARACTERISTICS

Parameter	Note S	Symbol	Condition	Value		Unit	
raiailletei	Note	Symbol	Condition	Min.	Max.		
Input Leakage Current		Sılı	$0 \text{ V} \leq V_{IN} \leq V_{CC}$	<b>–10</b>	10	μΑ	
Output Leakage Current		SILO	0 V ≤ Vout ≤ Vcc	-10	10	μΑ	
Output Low Voltage	*1	Svol	IoL = 3.0 mA	-	0.4	V	

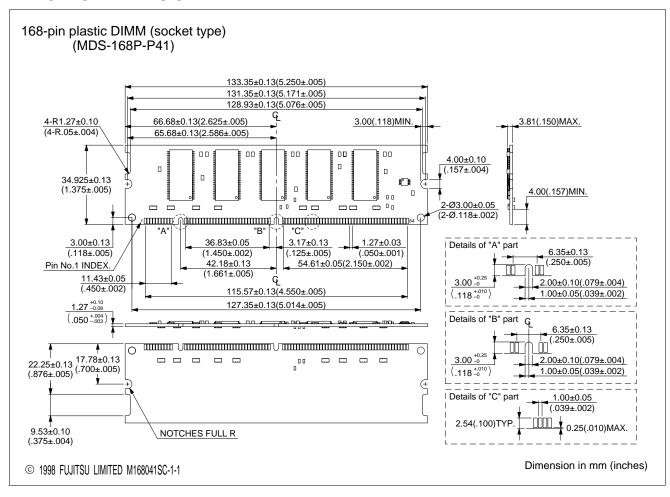
Note: \*1. Referenced to Vss.

### 5. AC CHARACTERISTICS

No.	Parameter	Symbol	Va	l lnit	
		Symbol	Min.	Max.	Unit
1	SCL Clock Frequency	fscL	_	100	KHz
2	Noise Suppression Time Constant at SCL, SDA Inputs	Tı	_	100	ns
3	SCL Low to SDA Data Out Valid	<b>t</b> AA	_	3.5	μs
4	Time the Bus Must Be Free Before a New Transmission Can Start	<b>t</b> BUF	4.7	_	μs
5	Start Condition Hold Time	<b>t</b> hd:sta	4.0	_	μs
6	Clock Low Period	<b>t</b> Low	4.7	_	μs
7	Clock High Period	tніgн	4.0	_	μs
8	Start Condition Setup Time	tsu:sta	4.7	_	μs
9	Data in Hold Time	thd:dat	0	_	μs
10	Data in Setup Time	tsu:dat	250	_	ns
11	SDA and SCL Rise Time	t <sub>R</sub>	_	1	μs
12	SDA and SCL Fall Time	t⊧	_	300	ns
13	Stop Condition Setup Time	tsu:sto	4.7	_	μs
14	Data Out Hold Time	tон	100	_	ns
15	Write Cycle Time	twr	_	15	ms



#### **■ PACKAGE DIMENSION**



## **FUJITSU LIMITED**

For further information please contact:

#### Japan

FUJITSU LIMITED
Corporate Global Business Support Division
Electronic Devices
KAWASAKI PLANT, 4-1-1, Kamikodanaka
Nakahara-ku, Kawasaki-shi

Kanagawa 211-8588, Japan Tel: 81(44) 754-3763

Fax: 81(44) 754-3329

http://www.fujitsu.co.jp/

#### **North and South America**

FUJITSU MICROELECTRONICS, INC. Semiconductor Division 3545 North First Street San Jose, CA 95134-1804, USA

Tel: (408) 922-9000 Fax: (408) 922-9179

Customer Response Center Mon. - Fri.: 7 am - 5 pm (PST)

Tel: (800) 866-8608 Fax: (408) 922-9179

http://www.fujitsumicro.com/

#### **Europe**

FUJITSU MIKROELEKTRONIK GmbH Am Siebenstein 6-10 D-63303 Dreieich-Buchschlag Germany

Tel: (06103) 690-0 Fax: (06103) 690-122

http://www.fujitsu-ede.com/

#### **Asia Pacific**

FUJITSU MICROELECTRONICS ASIA PTE LTD #05-08, 151 Lorong Chuan New Tech Park

Singapore 556741 Tel: (65) 281-0770 Fax: (65) 281-0220

http://www.fmap.com.sg/

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